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**INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT**  
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Complete If Known

Application Number	Unknown 10/789736
Filing Date	Even Date Herewith 2/27/04
First Named Inventor	Yin, Zhiping
Group Art Unit	Unknown 2891
Examiner Name	Unknown WILSON

Sheet 1 of 1

Attorney Docket No: 303.885US1

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	US-5,096,791	03/17/1992	Yahalom, Joseph	430	5	11/29/1989
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Examiner Initials*	Foreign Document No	Publication Date	Name of Patentee or Applicant of cited Document	Class	Subclass	T <sup>2</sup>
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Examiner Initials*	Cite No <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
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Christina Wilson

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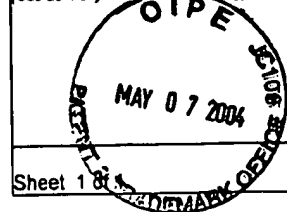
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First Named Inventor	Yin, Zhiping
Group Art Unit	Unknown 2891
Examiner Name	Unknown WILSON

Attorney Docket No: 303.885US1

Sheet 1 of 1

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Examiner Initial *	USP Document Number	Publication Date	Name of Patentee or Applicant of cited Document	Class	Subclass	Filing Date if Appropriate
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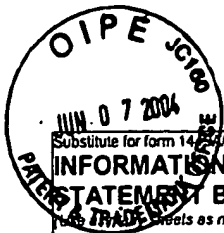
Examiner Initials*	Cite No	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
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EXAMINER *Christina Wilson*

DATE CONSIDERED 1/17/06

Substitute Disclosure Statement Form (PTO-1449)

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Complete if Known

Application Number	10/789736
Filing Date	February 27, 2004
First Named Inventor	Yin, Zhiping
Group Art Unit	<del>2811</del> 2891
Examiner Name	Unknown WILSON

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Attorney Docket No: 303.885US1

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Examiner Initial *	USP Document Number	Publication Date	Name of Patentee or Applicant of cited Document	Class	Subclass	Filing Date If Appropriate
OW	US-5,750,316	05/12/1998	Kawamura, Eiichi, et al.	430	311	03/15/1995

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Application Number	10/789,736
Filing Date	February 27, 2004
First Named Inventor	Yin, Zhiping
Group Art Unit	2891
Examiner Name	Wilson, Christian

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Attorney Docket No: 303.885US1

**US PATENT DOCUMENTS**

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First Named Inventor	Yin, Zhiping
Group Art Unit	2891
Examiner Name	Wilson, Christian

Sheet 2 of 2

Attorney Docket No: 303.885US1

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Examiner Initials*	Cite No <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
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